ABSTRACT OF THE DISCLOSURE

In a gate electrode, above a first
polycrystalline silicon film, a second
polycrystalline silicon film, which has a
predetermined silicon crystal face orientation
directed with respect to and is smaller in crystal
diameter than the first polycrystalline silicon film,
is provided, so that even if there locally exist
portions which are different in silicidization speed
in forming a silicide layer in the second
polycrystalline silicon film, the silicidization
reaction with unreacted portions of the second
polycrystalline silicon film can occur faster than
the silicidization reaction with the first
polycrystalline silicon film.